## Analysis of periodicity in arrays of triple steps on vicinal surfaces: Period-dependent suppression of Fourier peaks

A. Yu. Aladyshkin<sup>1,2,3</sup>\*, A. N. Chaika<sup>4</sup>, V. N. Semenov<sup>4</sup>, A. M. Ionov<sup>4</sup>, S. I. Bozhko<sup>4</sup>

<sup>1</sup> Moscow Institute of Physics and Technology, Dolgoprudny, Russia

<sup>2</sup> Institute for Physics of Microstructures RAS, Nizhny Novgorod, Russia

<sup>3</sup> Lobachevsky State University of Nizhny Novgorod, Nizhny Novgorod, Russia

<sup>4</sup> Osipyan Institute of Solid State Physics RAS, Chernogolovka, Russia

\*email: aladyshkin.au@mipt.ru

**Key words**: High-index-Miller surfaces, 7×7 reconstruction, Fourier analysis, triple steps

We have investigated the peculiarities of atomic structures on vicinal surfaces Si(h h m), oriented at an angle close to  $9.5^{\circ}$  relative to the terraces (1 1 1). As a result, we have to consider the following surfaces: Si(8 8 11) (miscut angle of  $8.93^{\circ}$ , period of triple steps of  $L_3=18b=5.99$  nm, where b=0.335 nm is the distance between atomic rows for the surface  $Si(1 1 1)1\times1$  in the [1 1 2] direction), Si(5 5 7) (9.44°,  $L_3=17b=5.65$  nm) and Si(7 7 10) (10.0°,  $L_3=16b=5.32$  nm). The expected difference in periods for these surfaces is rather small (about 6%) and can be easily masked by distortions in the scanning plane caused by thermal drift and/or creep of piezo scanner. We propose a novel method for determining the periodicity of a system of triple steps.

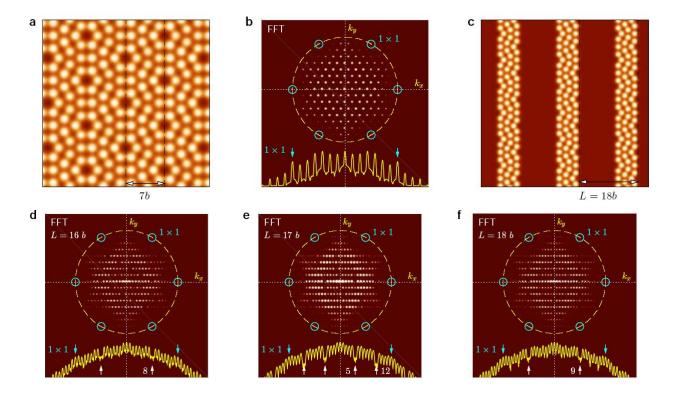


Fig. 1. **a, b** – Model surface Si(1 1 1)7×7 and corresponding Fourier transform  $z(k_x, k_y)$ , yellow curve in the bottom part of panel b depicts the dependence  $\ln |z(k_x, k_y=0)|$ . **c** – A fragment of the model structure representing periodically repeating strips of the Si(1 1 1)7×7 reconstructions with period L. **d-f** – Fourier transform  $z(k_x, k_y)$  for the periodical patterns with periods 16b (d), 17b (e) and 18b (f). The radius of the circle marking the expected positions of the first-order Fourier peaks for the Si(1 1 1) 7×7 lattice, is equal to 18.89 nm<sup>-1</sup>.

We note that there are areas with  $7\times7$  reconstruction on (1 1 1) terraces for vicinal surfaces Si(8 8 11), Si(5 5 7), and Si(7 7 10) (Fig. 1c). We have shown that the Fourier transforms of topography images for such structures could contain split Fourier peaks (Fig. 1, panels d-f). Depending on the period of the superstructure, one or two peaks on the dependence of  $|z(k_x,k_y)|$ , composed for  $k_y$ =0, become suppressed. This enables us to uniquely determine the structure period and establish Miller indices for the considered vicinal surfaces. For vicinal surface Si(h h m), studied experimentally, proper alignment can be done using the difference-of-Gaussian approach [1]. Fourier analysis of differential topographic images obtained by scanning tunneling microscopy unequivocally indicates suppression of the ninth Fourier peak (at  $k_x$ = 9,45 nm<sup>-1</sup> and  $k_y$ =0, Fig. 1f). It apparently corresponds to the formation of Si(8 8 11) surface [2].

## Bibliography

- [1] A. Yu. Aladyshkin et al., Ultramicroscopy, v. 267, 114053 (2024).
- [2] A. Yu. Aladyshkin et al., submitted (2025).